

<b>Notice of References Cited</b>	Application/Control No. 10/691,395	Applicant(s)/Patent Under Reexamination SAIGA ET AL.	
	Examiner Haoshian Shih	Art Unit 2196	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,279,017 b1	08-2001	Walker, Randall C.	715/529
*	B	US-2003/0235807 a1	12-2003	Paley, W. Bradford	434/178
*	C	US-6,181,909 b1	01-2001	Burstein et al.	434/353
*	D	US-5,761,682 a	06-1998	Huffman et al.	715/500
*	E	US-4,437,837 a	03-1984	Schnettler et al.	434/178
*	F	US-6,003,393 a	12-1999	Kimura et al.	74/89.28
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	WYNN 2 in depth, Freedom Scientific. 1998 Arkenstone, Inc. <a href="http://www.freedomscientific.com/LSG/downloads/InDepthWYNN2.txt">www.freedomscientific.com/LSG/downloads/InDepthWYNN2.txt</a>
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.